

~ Campaign Information ~

XPS Analysis Special Offer

50,000

YEN
(excluding tax)
**per
sample**

Campaign Period

June 1, 2026 (Mon) ~ August 28, 2026 (Fri)

Measurement Items

Surface survey + Narrow scan (up to **6 elements**) + Curve fitting

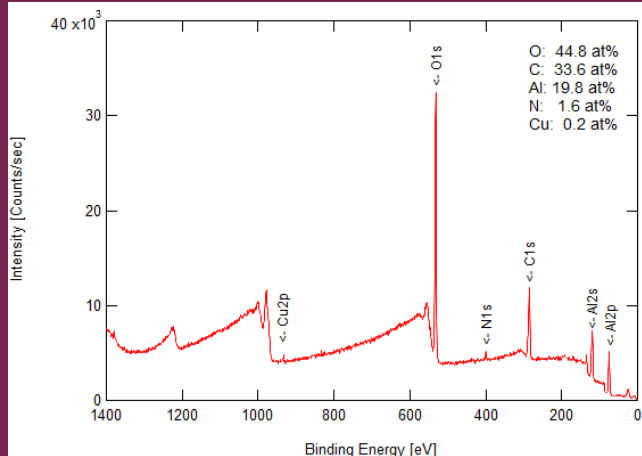


Fig-1 : Survey spectrum of the oxidized layer on the Al surface

Along with Al from the substrate, O from the oxide layer, and C from surface contamination, other impurities such as N and Cu are also detected.

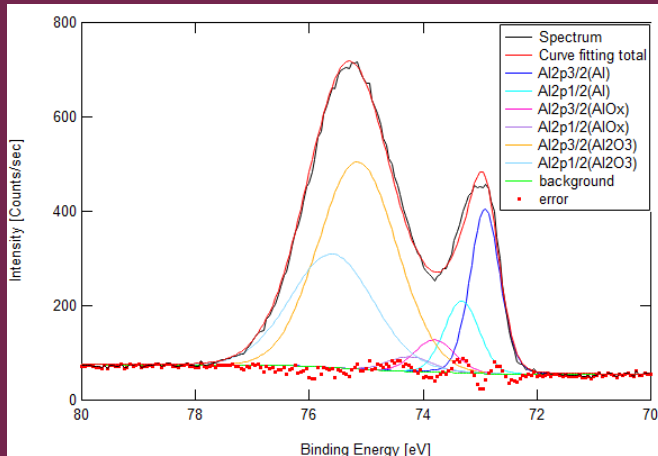


Fig-2 : Curve fitting analysis of the oxidized layer on the Al surface

In addition to aluminum oxide (the oxide layer), intermediate composition are identified on the substrate Al surface.

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